Search Notes

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09/853,770 Examiner

Ellen C. Tran

Applicant(s)/Patent under Reexamination

SHIGEMATSU ET AL.

Art Unit

2134

SEARCHED					
Class	Subclass	Date	Examiner		
713	186	12/21/2007	ET		
726	9, 10	12/21/2007	ET		
726	18, 19	12/21/2007	ET		
726	20	12/21/2007	ET		
713	185	12/21/2007	ET		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	12/21/2007	ΕT
NPL - IEEE XPLORE	12/21/2007	ET
ALL CLAIMS WERE REVIEWED FOR POSSIBLE 101 REJECTIONS	12/21/2007	ET